## **Notice of References Cited**

Application/Control No. 09/464,322

Applicant(s)/Patent Under Reexamination KWON ET AL.

Examiner

Chris C. Chu

Art Unit 2815

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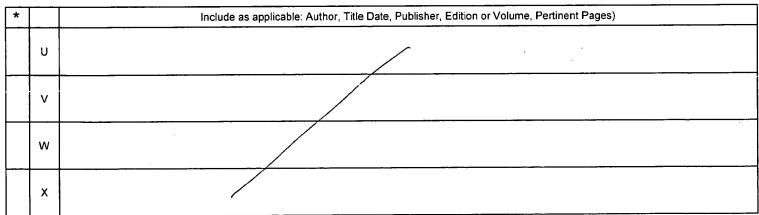
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.